

## BEST AVAILABLE COPY

PATENT NUMBER

U.S. UTILITY Patent Application
O.I.P.E. PATENT DATE

AF	PLICATION NO. 09/927444	CONT/PRIOR	CLASS 438	SUBCLASS 121	ART UNIT 2812	EXAMINER Shechtmaa				
APPLICANTS	Nicholas Ward Richard Danielson David Corey									
щ	Dynamic c manufactu	ontrol of ring prod	F wafer p Jesses	processing	paths in	semiconductor				

ISSUING CLASSIFICATION											
ORIGINAL			CROSS REFERENCE(S)								
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)								
INTERNATIONAL	CLASSIFICATION										
			Continued on Issue Slip Inside File Jacket								

I	DRAWINGS			CLAIMS ALLOWED		
Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims	Print Claim for O.G.		
<u></u>			NOTICE OF ALLOWANCE MAILED			
(Assistant Examiner)		(Date)				
			ISSUE FEE			
			Amount Due	Date Paid		
(Primary E	(Primary Examiner)					
			ISSUE BAT	TCH NUMBER		
(Legal Instrume	ents Examiner)	(Date)				
				5, Sections 122, 181 and 388		
	(Assistant (Primary to (Logal Instrumentstricted, Unauthorized)	(Assistant Examiner)  (Primary Examiner)  (Logal Instruments Examiner)	(Assistant Examiner) (Oate)  (Primary Examiner) (Oate)  (Logal Instruments Examiner) (Oate)	(Assistant Examiner) (Oate)  ISSI Amount Due  (Primary Examiner) (Oate)		